



DE LA RECHERCHE À L'INDUSTRIE

Polynomial chaos-based uncertainty quantification of material parameters

May 14, 2022

Loïc GIRALDI – IRESNE / DEC / SESC / LSC

Loic.GIRALDI@cea.fr



► CV



- **2009-2015 @ Centrale Nantes : PhD + post-doc**
 - Uncertainty propagation for high dimensional problems
 - Semi-intrusive uncertainty propagation
- **2015-2018 @ KAUST : Post-doc**
 - Uncertainty quantification and data assimilation applied to geosciences
- **2018-2020 @ Renault : Data Scientist**
 - Uncertainty quantification and AI for the digital validation of autonomous vehicles
- **Since 2020/12/21 @ CEA : Research Scientist**
 - Uncertainty quantification and AI for nuclear fuel performance simulations

► Research topics

- Uncertainty quantification
- AI and data assimilation
- Numerical methods for model order reduction

► Uncertainty quantification definition

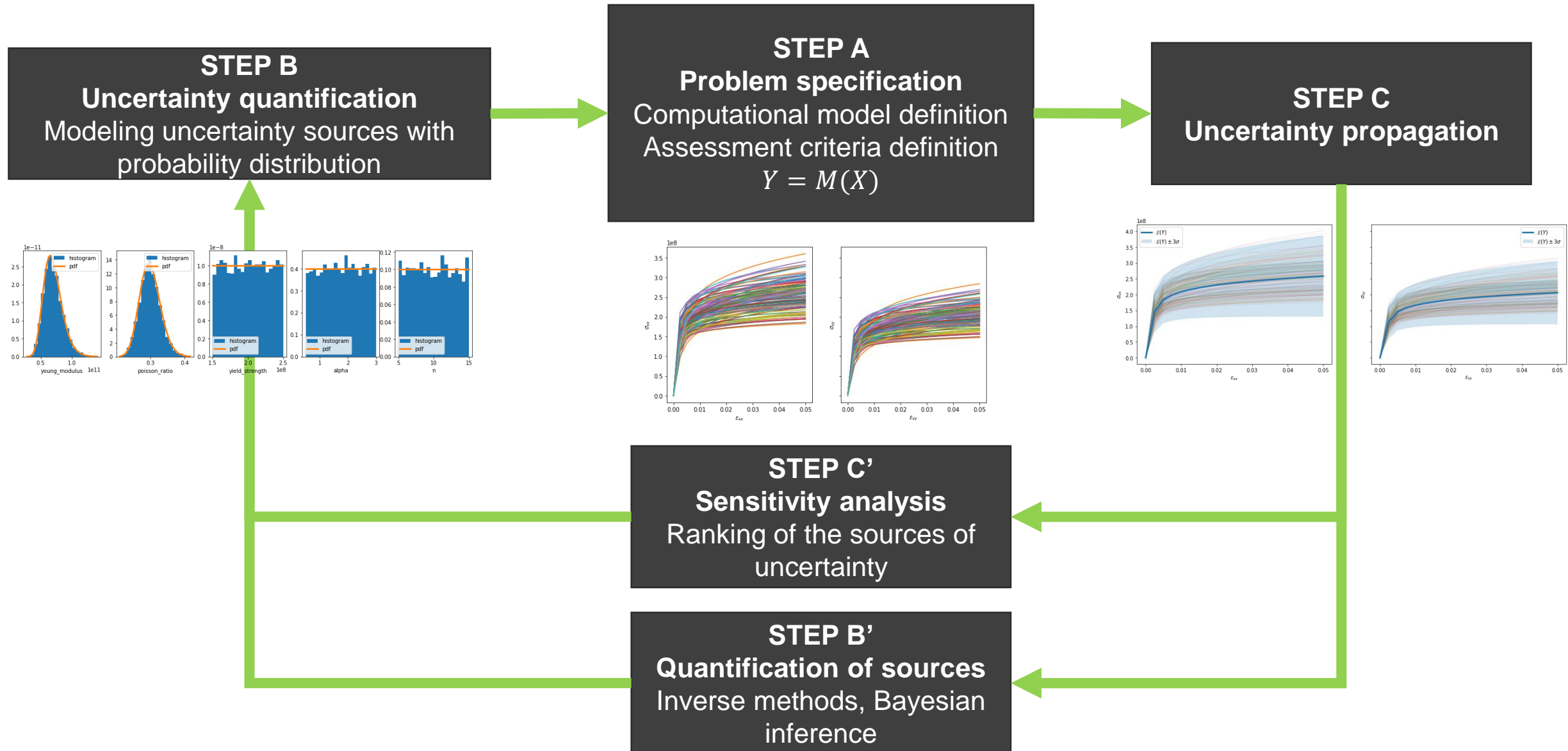
- Science of **quantifying** and **reducing** uncertainties in computational and real-world systems

► Classification of uncertainty sources

- **Epistemic uncertainty:** uncertainty that comes from a lack of knowledge, **can be reduced**
 - **Example:** my height, material parameters,...
- **Aleatoric uncertainty:** uncertainty that differs each time we run the experiment, **cannot be reduced**
 - **Example:** rolling a dice,...

► Aim of the course

- Perform the uncertainty quantification of material parameters from a tensile test and a shear test
 - Knowledge of the uncertainty quantification process
 - Perform the different steps of the above process



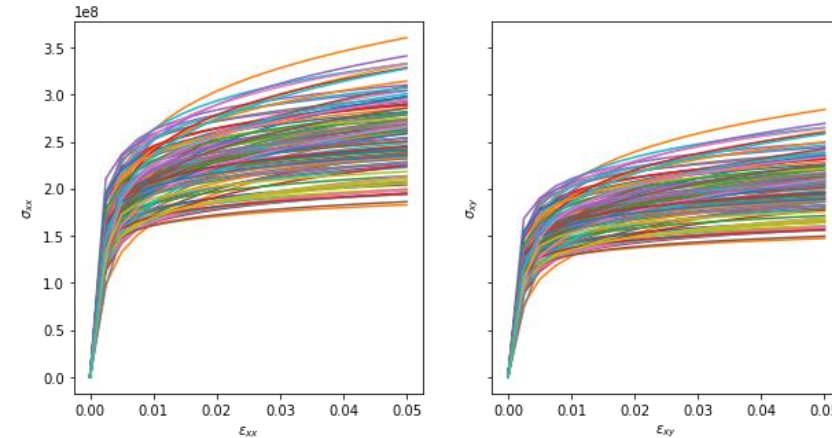
- Simulation of a tensile test and a shear test with MFront / Mtest (tfel.sourceforge.net/index.html)

- Nonlinear elastic Ramberg-Osgood constitutive behavior

$$\varepsilon = \frac{1}{3K} \text{tr}(\sigma) I + \frac{\sigma_{VM}}{3\mu} n_{VM} + \alpha \left(\frac{\sigma_{VM}}{\sigma_0} \right)^n n_{VM}.$$

- where

- E is the Young modulus,
- ν is the Poisson ratio,
- $K = E/(3(1 - 2\nu))$ is the bulk modulus,
- $\mu = E/(2(1 + \nu))$ is the shear modulus,
- σ_0 is the yield strength, α and n are numerical parameters describing the pseudo-plastic part of the behavior,
- σ_{VM} is the Von Mises equivalent stress,
- n_{VM} is the Von Mises normal



- Tensile test : displacement / strains are imposed such that $\varepsilon = \begin{pmatrix} \varepsilon_{xx} & 0 & 0 \\ 0 & * & 0 \\ 0 & 0 & * \end{pmatrix}$, and we measure σ_{xx}

- Shear test : displacement / strains are imposed such that $\varepsilon = \begin{pmatrix} * & \varepsilon_{xy} & 0 \\ \varepsilon_{xy} & * & 0 \\ 0 & 0 & * \end{pmatrix}$, and we measure σ_{xy}

- Computational model

$$X = (E, \nu, \sigma_0, \alpha, n) \mapsto Y(X) = (\sigma_{xx}^0, \dots, \sigma_{xx}^t, \sigma_{xy}^0, \dots, \sigma_{xy}^t) \in \mathbb{R}^T, \quad T = 2(t + 1)$$

► Material parameters

- E is the Young modulus,
- ν is the Poisson ratio,
- σ_0 is the yield strength,
- α and n are numerical parameters describing the pseudo-plastic part of the behavior.

► Probability distribution of the parameters

- The Young modulus E is drawn according to a **log-normal distribution**,
- The Poisson ratio ν is drawn according to a **log-normal distribution**,
- The parameters σ_0, α, n are assumed to be **uniform**.

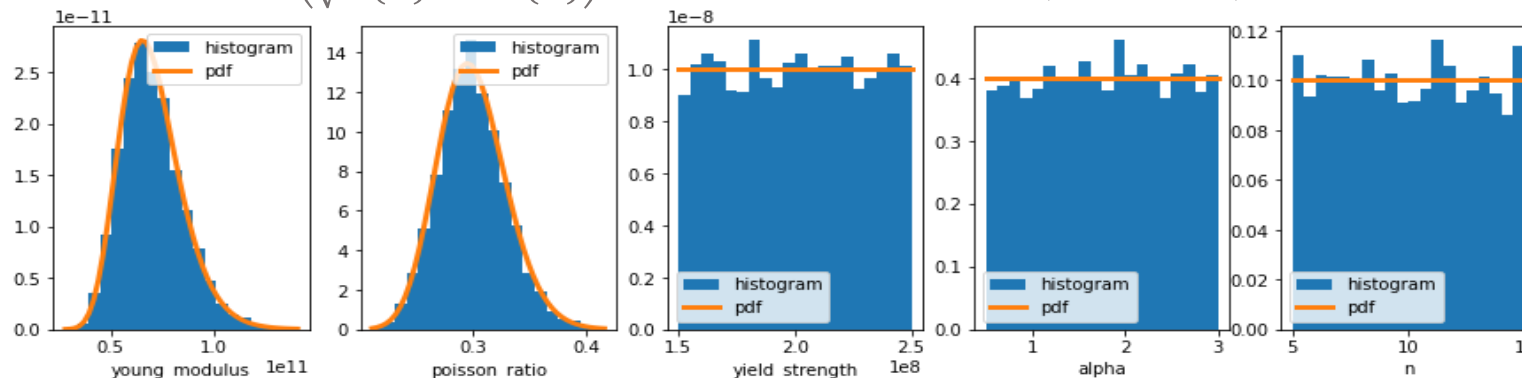
► Log-normal distribution crash course

- X follows a log-normal distribution if

$$X = \exp(\mu + \sigma Z) \quad \text{where} \quad Z \sim N(0,1)$$

- We can fully describe a log normal distribution through its mean $\mathbb{E}(X)$ and variance $\mathbb{V}(X)$ with the relations

$$\mu = \log\left(\frac{\mathbb{E}(X)^2}{\sqrt{\mathbb{E}(X)^2 + \mathbb{V}(X)}}\right), \quad \text{and} \quad \sigma = \log\left(1 + \frac{\mathbb{V}(X)}{\mathbb{E}(X)^2}\right).$$



► Issues

- Evaluating statistics, probabilities, quantities of interest requires **a large number of evaluations** of the model
- Optimization based approaches require the **gradient** of the model

► Solution

- **Surrogate modeling (metamodeling)** in order to replace the computational model
- Approaches in the literature : **polynomial chaos expansion**, Gaussian processes, **machine learning models**, ...

► Generalized Polynomial Chaos Expansion

- Assume that the random variable Y has a finite variance, then Y admits the decomposition

$$Y(X) = \sum_{k=0}^{\infty} w_k \phi_k(X).$$

- $(\phi_k)_{k=0}^{\infty}$ is a family of multivariate orthogonal polynomials for the L^2 inner product

$$\langle \phi_k, \phi_l \rangle = \mathbb{E}(\phi_k \phi_l) = \int_{\mathcal{X}} \phi_k(x) \phi_l(x) p(x) dx = \delta_{kl} \|\phi_k\|^2.$$

► Expression of the truncated polynomial chaos expansion for independent random variables

- X_1, \dots, X_d are assumed to be independent random variables such that the basis becomes

$$\phi_\alpha(X) = \phi_{\alpha_1}^1(X_1) \dots \phi_{\alpha_d}^d(X_d)$$

- where $(\phi_k^i)_{k=0}^\infty$ is family of univariate polynomials orthogonal with respect to the density $p(X_i)$
- We assume that $\deg(\phi_k^i) = k$
- We then discretize the series such that

$$Y(X) \approx Y_{PC}(X) = \sum_{k=0}^P w_k \phi_k(X) = \sum_{\alpha \in \mathcal{J}} w_\alpha \phi_{\alpha_1}^1(X_1) \dots \phi_{\alpha_d}^d(X_d).$$

- Where $\mathcal{J} \subset \mathbb{N}^d$ is a **finite set** of multi-indices such that $\#\mathcal{J} = P + 1$.

► Some truncation strategies – definition of the multi-index set

- Full tensorization of the polynomial basis

$$\mathcal{J} = \{\alpha \in \mathbb{N}^d; \alpha_i \leq D_i\}$$

- Total degree based truncation

$$\mathcal{J} = \{\alpha \in \mathbb{N}^d; \sum \alpha_i \leq D\}$$

► Choice of the univariate polynomials

Probability distribution	Orthogonal polynomials
Gaussian distribution $\mathcal{N}(0,1)$	Hermite
Uniform distribution $\mathcal{U}(-1, 1)$	Legendre

1. Transform the random variable / dataset

- For log-normal distributions $X = \exp(\mu + \sigma Z)$, we have $Z = \frac{\log(X) - \mu}{\sigma} \sim \mathcal{N}(0,1)$
- For uniform distributions $X = \mathcal{U}(a, b)$, we have $Z = \frac{b-a}{2}X + \frac{b+a}{2} \sim \mathcal{U}(-1,1)$
- Now, we look for an expansion of the form

$$Y(Z) \approx Y_{PC}(Z) = \sum_{\alpha \in \mathcal{J}} w_{\alpha} \phi_{\alpha}(Z)$$

2. Pick the right polynomials associated to the reference distributions

3. Define the truncation scheme via the set of multi-indices \mathcal{J}

4. Compute the optimal weights $(w_{\alpha})_{\alpha \in \mathcal{J}}$ by solving the regression problem given a dataset $(z_i, y_i)_{i=1}^N$

$$\min_w \frac{1}{N} \sum_{i=1}^N \left\| y_i - \sum_{\alpha \in \mathcal{J}} w_{\alpha} \phi_{\alpha}(z_i) \right\|^2$$

► Model selection is performed via hold-out validation

Dataset splitting:



Computation of w

Selection of the best model
(degree, truncation,...)

Assessment of the quality of the
selected model

- Given a polynomial chaos expansion

$$Y_{PC}(Z) = \sum_{\alpha \in \mathcal{I}} w_{\alpha} \phi_{\alpha}(Z)$$

- We can compute some interesting quantities of interest by post-processing

- Evaluating the model at a sample z requires the evaluation of the basis $(\phi_{\alpha}(z))_{\alpha \in \mathcal{I}}$ and computing the product with the weights $(w_{\alpha})_{\alpha \in \mathcal{I}}$

- The expectation is

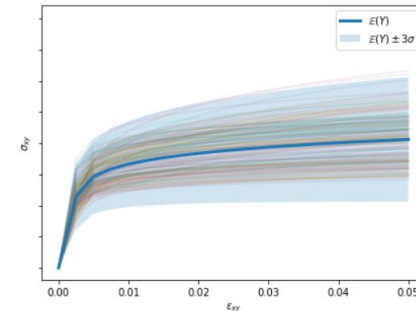
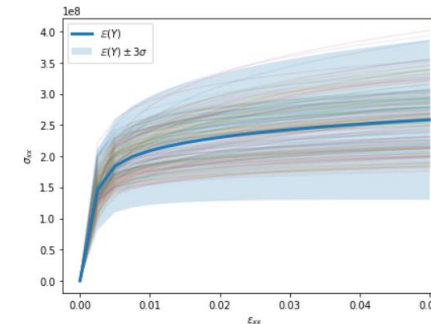
$$\mathbb{E}(Y_{PC}(Z)) = w_0$$

- The variance is

$$\mathbb{V}(Y_{PC}(Z)) = \sum_{\alpha \in \mathcal{I} \setminus \{0\}} w_{\alpha}^2 \|\phi_{\alpha}\|^2$$

- The gradient of the polynomial chaos

$$\frac{\partial Y_{PC}}{\partial Z_i}(Z) = \sum_{\alpha \in \mathcal{I}} w_{\alpha} \phi_{\alpha_1}^1(Z_1) \dots (\phi_{\alpha_i}^i)'(Z_i) \dots \phi_{\alpha_d}^d(Z_d)$$



- **Variance-based sensitivity analysis:** quantify the proportions of the model output variance induced by the uncertainties of each input parameter
- **The Sobol decomposition exists and is unique for random variables with finite variance and orthogonality condition**

$$Y(Z) = Y_0 + \sum_{i=1}^d Y_i(Z_i) + \sum_{i < j}^d Y_{ij}(Z_i, Z_j) + \dots + Y_{1\dots d}(Z_1, \dots Z_d)$$

- **The orthogonality condition implies that we can decompose the variance such that**

$$\mathbb{V}(Y) = \sum_{i=1}^d \mathbb{V}(Y_i) + \sum_{i < j}^d \mathbb{V}(Y_{ij}) + \dots + \mathbb{V}(Y_{1\dots d})$$

or, $1 = \sum_{i=1}^d S_i + \sum_{i < j}^d S_{ij} + \dots + S_{1\dots d}$ where $S_u = \frac{\mathbb{V}(Y_u)}{\mathbb{V}(Y)}$

- The quantities $(S_u)_u$ are called **first-order Sobol indices** and quantify the proportion of the variance of Y induced by the variables in u .
- S_i quantify the variance induced by the variable Z_i alone.
- The quantity of variance induced by Z_i and its interactions with the other variables is the **total order Sobol index T_i** defined by

$$T_i = \sum_{\substack{u \\ i \in u}} S_u$$

- Sobol indices are post-processes from polynomial chaos expansions

$$Y_{PC}(Z) = \sum_{\alpha \in \mathcal{I}} w_{\alpha} \phi_{\alpha_1}^1(Z_1) \dots \phi_{\alpha_d}^d(Z_d)$$

- The variance is

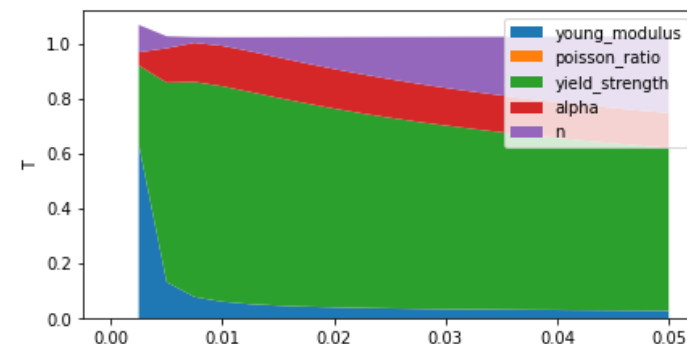
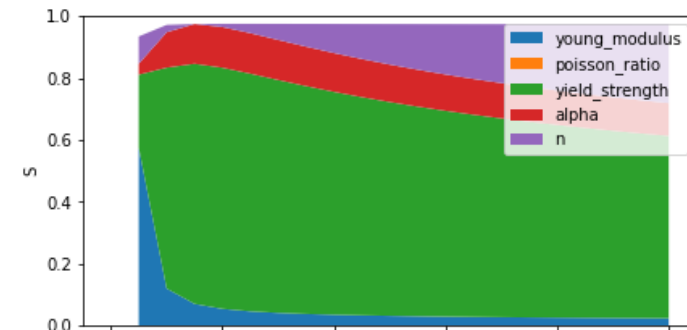
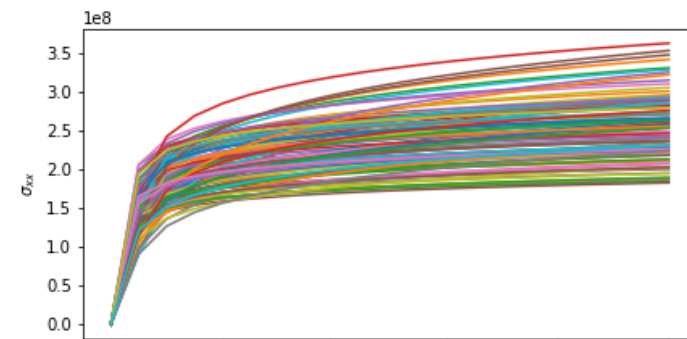
$$\mathbb{V}(Y_{PC}(Z)) = \sum_{\alpha \in \mathcal{I} \setminus \{0\}} w_{\alpha}^2 \|\phi_{\alpha}\|^2$$

- The first-order Sobol index S_i is

$$S_i = \frac{1}{\mathbb{V}(Y_{PC}(Z))} \sum_{\substack{\alpha \in \mathcal{I} \\ \alpha = (0, \dots, 0, \alpha_i, 0, \dots, 0)}} w_{\alpha}^2 \|\phi_{\alpha}\|^2$$

- The total-order Sobol index T_i is

$$T_i = \frac{1}{\mathbb{V}(Y_{PC}(Z))} \sum_{\substack{\alpha \in \mathcal{I} \\ \alpha_i > 0}} w_{\alpha}^2 \|\phi_{\alpha}\|^2$$



► Issue

- The distribution of X (or Z) was defined at the beginning.
- An experiment was performed and some data y_e were collected. The experimental process is assumed to satisfy
$$Y_e = Y(Z) + \varepsilon, \quad \varepsilon \sim \mathcal{N}(0, \sigma^2 \mathbb{I})$$
- How can we **update the distribution** of the parameter X **after having observed the data**?

► Bayes theorem states that

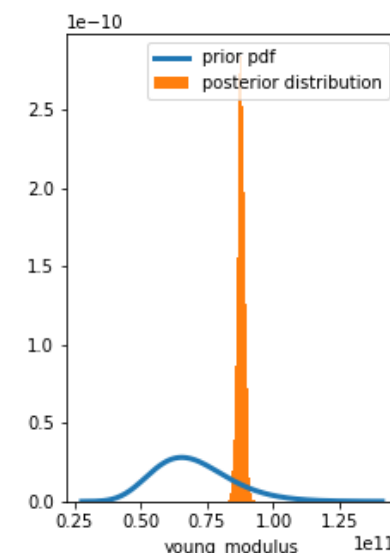
$$p(Z | Y_e = y_e) = \frac{p(Y_e = y_e | Z)p(Z)}{p(Y_e = y_e)}$$

- $p(Z | Y_e = y_e)$ is the **posterior distribution**, i.e. the updated distribution of Z after seeing the data y_e ,
- $p(Y_e = y_e | Z)$ is the **likelihood**, describing the probability of the data $Y_e = y_e$ knowing the parameter Z
- $p(Z)$ is the **prior distribution**, the distribution of Z before having observed any data
- $p(Y_e = y_e)$ is the **model evidence**, the probability of the data (scaling factor).

► Bayesian inference is a method to update the distribution of Z after knowing some data.

► Common objectives related to Bayesian inference

- Estimate the value z_{MAP} with the maximum posterior distribution density
- Approximate the posterior distribution
- Sample from the posterior distribution (MCMC)



► Objective

- Compute the **Maximum A Posteriori estimate** z_{MAP} maximizing the posterior distribution density such that

$$\log p(z_{MAP} | Y_e = y_e) = \max_z \log p(z | Y_e = y_e)$$

► Since $Y_e = Y(Z) + \varepsilon$ with $\varepsilon \sim \mathcal{N}(0, \sigma^2 \mathbb{I})$, the likelihood is

$$p(Y_e | Z) \sim \mathcal{N}(Y(Z), \sigma^2 \mathbb{I})$$

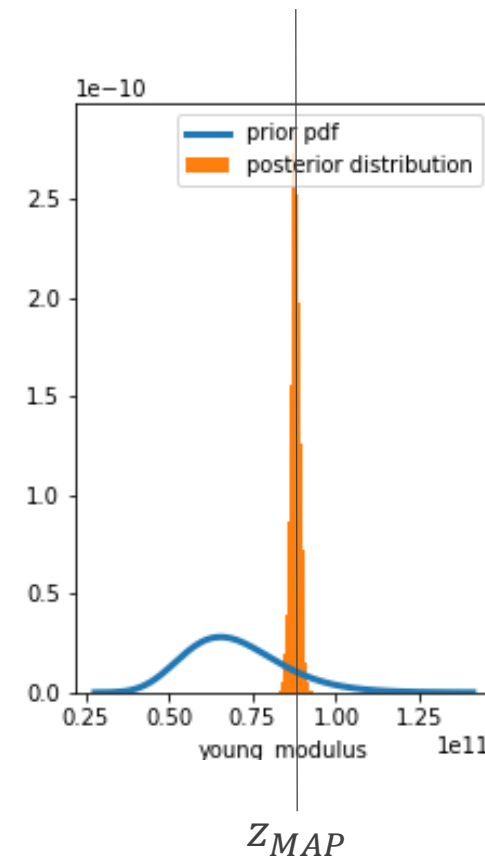
► Bayes theorem yields

$$\log p(Z | Y_e = y_e) = -\frac{1}{2} \frac{\|y_e - Y(Z)\|^2}{\sigma^2} + \log p(Z) - \log p(Y_e = y_e)$$

► We can therefore compute the MAP estimate by solving the optimization problem

$$z_{MAP} \in \arg \max_z \underbrace{-\frac{1}{2} \frac{\|y_e - Y(z)\|^2}{\sigma^2}}_{\text{Least square problem}} + \underbrace{\log p(Z)}_{\text{penalty function}}$$

Least square problem with a penalty function



► **Objective**

- Approximate the posterior distribution by a variational distribution $q_{\theta}(Z)$ with parameters θ

$$q_{\theta}(Z) \approx p(Z \mid Y_e = y_e)$$

► **Methodology**

- **Mean field approximation** of the posterior distribution (dependences are lost)

$$q_{\theta}(Z) = q_{\theta}^1(Z_1) \dots q_{\theta}^d(Z_d)$$

- Computation of the optimal distribution by minimization of a **Kullback-Leibler divergence** (“distance”) between distributions

$$\min_{\theta} KL(q_{\theta}(Z) \parallel p(Z \mid Y_e = y_e)) = \mathbb{E}_{q_{\theta}} \left(\frac{\log q_{\theta}(Z)}{\log p(Z \mid Y_e = y_e)} \right)$$

- Minimizing the Kullback-Leibler divergence is equivalent to maximizing the **Evidence Lower Bound**

$$\max_{\theta} \mathcal{L}(q_{\theta}) = \mathbb{E}_{q_{\theta}}(\log p(Y_e = y_e \mid Z) + \log p(Z) - \log q_{\theta}(Z))$$

► Maximization of the ELBO

$$\max_{q_\theta} \mathcal{L}(q_\theta) = \mathbb{E}_q(\log p(Y_e = y_e | Z) + \log p(Z) - \log q_\theta(Z))$$

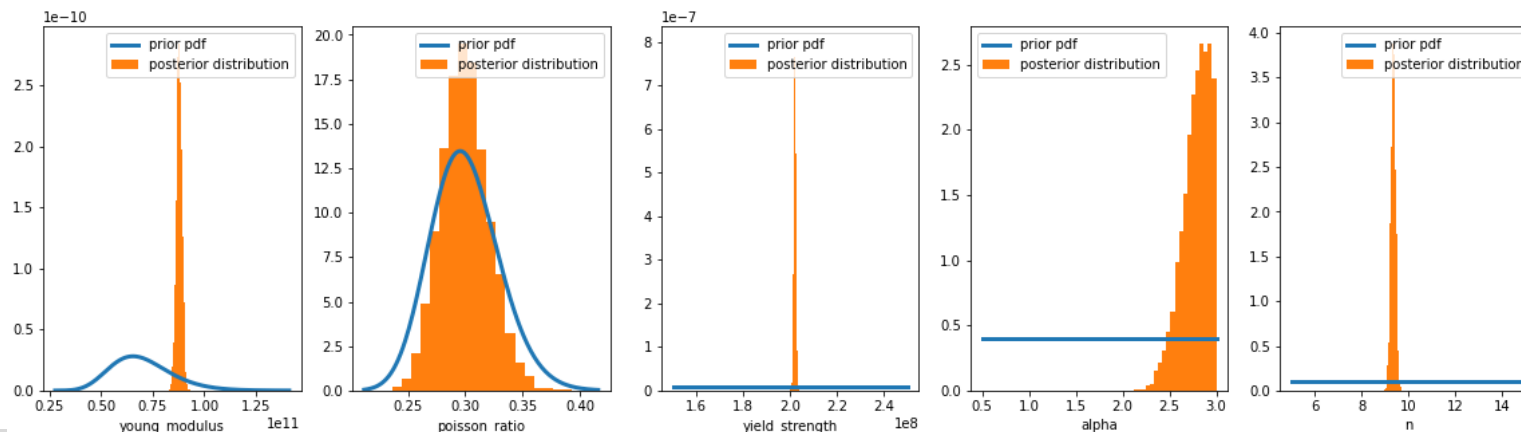
► Monte-Carlo approximation of the ELBO and its gradient

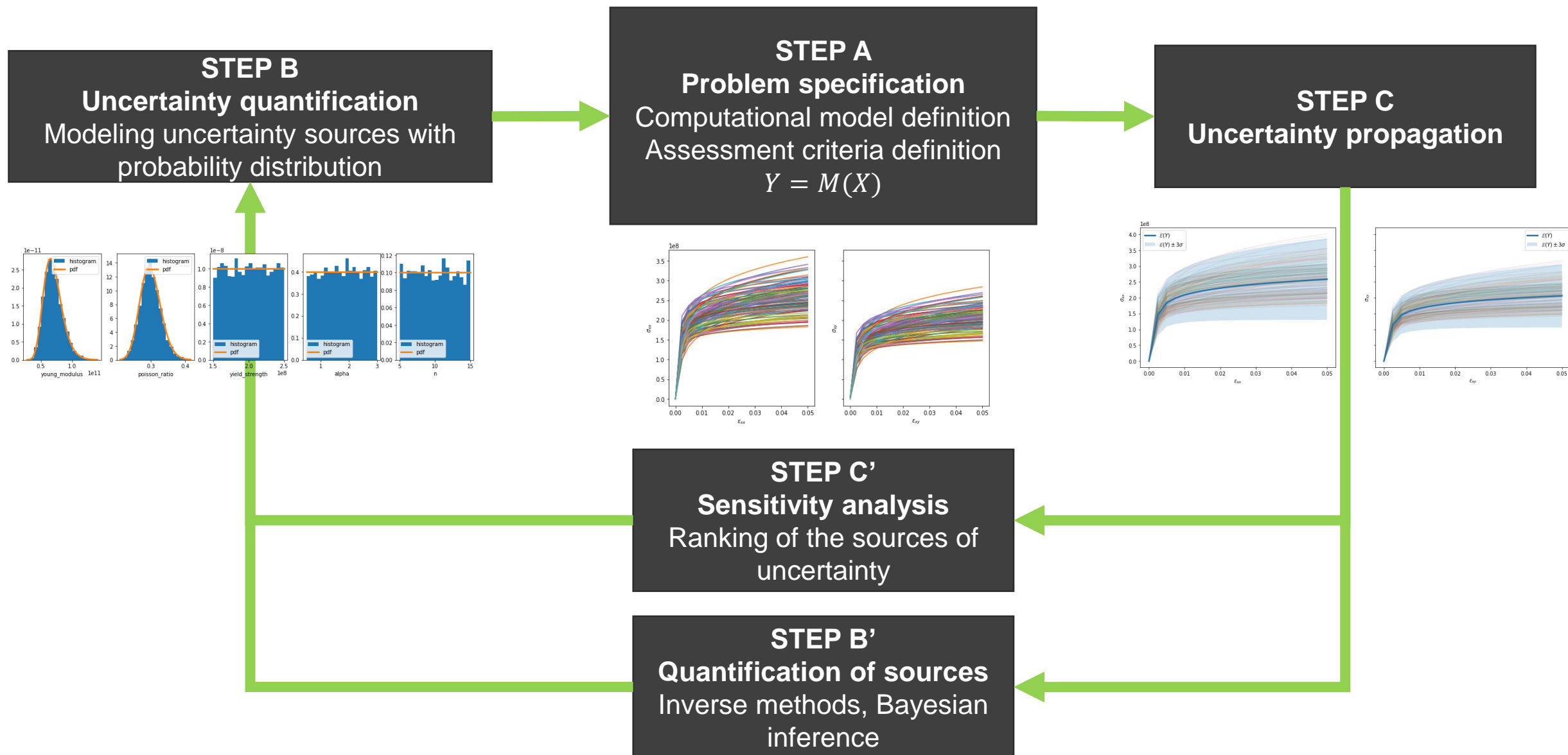
$$\mathcal{L}(q_\theta) \approx \frac{1}{N} \sum_{i=1}^N \log p(Y_e = y_e | z_i) + \log p(z_i) - \log q_\theta(z_i)$$

$$\nabla_\theta \mathcal{L}(q_\theta) \approx \frac{1}{N} \sum_{i=1}^N (\nabla_\theta \log q_\theta(z_i)) (\log p(Y_e = y_e | z_i) + \log p(z_i) - \log q_\theta(z_i))$$

► Optimization by stochastic gradient ascent – **Black-box Variational Inference algorithm**

- Initialize $\theta, \rho > 0, N$
- While θ has not converged:
 - Sample $(z_i)_{i=1}^N$ according to q_θ
 - Compute the Monte-Carlo approximation $\Delta\theta$ of $\nabla_\theta \mathcal{L}(q_\theta)$
 - $\theta \leftarrow \theta + \rho \Delta\theta$
- Return q_θ







Many thanks for your attention